

WHAT IS CLAIMED IS:

1. A testing apparatus having a plurality of testing module slots onto which different types of testing modules for generating different types of test signals to test a device under test are optionally mounted, comprising:

a plurality of controlling modules for supplying a control signal to each of said testing modules, said testing modules being mounted on said testing module slots respectively, said control signal being used for controlling said testing module;

setting information supplying means for supplying hardware setting information to a specific testing module among said testing modules, said hardware setting information being set in advance in said controlling module in order to send said control signal in response to said specific testing module;

enable signal controlling means for instructing said testing module to generate and supply an enable signal to said controlling module supplying said control signal to said testing module; and

setting means for setting a specific controlling module of said controlling modules to supply said control signal in response to said specific testing module to said specific testing module based on said hardware setting information, said specific controlling module receiving said enable signal from said specific testing module.

2. A testing apparatus as claimed in claim 1, wherein said controlling module comprises a plurality of interfaces for inputting different types of said control signals respectively,

said setting information supplying means selects a specific control signal among said control signals and supplies said

hardware setting information to said controlling module via a specific interface among said interfaces, said specific interface inputting said specific control signal to said controlling module, and

said setting means sets said controlling module to supply said specific control signal to said specific testing module, said specific control signal being inputted from said specific interface to said controlling module.

3. A testing apparatus as claimed in claim 2, wherein said controlling module further comprises:

a multiplexer circuit for selecting said specific control signal to be supplied to said specific testing module among said control signals inputted from said interfaces respectively; and

a flip-flop circuit for holding information indicating that said hardware setting information is inputted from said specific interface as a select signal for controlling said multiplexer circuit to select said specific control signal, based on a setting request signal supplied from said setting means, when said enable signal is received from said specific testing module.

4. A testing apparatus as claimed in claim 3, wherein said control signal is a trigger signal for controlling said testing module, and

said multiplexer circuit selects and supplies a trigger signal to be supplied to said specific testing module among different types of said trigger signals inputted from said interfaces respectively.

5. A testing apparatus as claimed in claim 3, wherein said

control signal is a clock signal for controlling said testing module, and

said multiplexer circuit selects and supplies a clock signal to be supplied to said specific testing module among different types of said clock signals inputted from said interfaces respectively.

6. A testing apparatus as claimed in claim 2, wherein said controlling module further comprises:

a first multiplexer circuit for selecting a trigger signal to be supplied to said specific testing module among different types of trigger signals for controlling said testing modules, said trigger signal being inputted from each of said interfaces as said control signal;

a first flip-flop circuit for holding information indicating that said hardware setting information is inputted from said specific interface as a select signal for controlling said first multiplexer circuit to select said trigger signal, based on a setting request signal supplied from said setting means, when said enable signal is received from said specific testing module;

a second multiplexer circuit for selecting a clock signal to be supplied to said specific testing module among different types of clock signals for controlling said testing modules, said clock signal being inputted from each of said interfaces as said control signal; and

a second flip-flop circuit for holding information indicating that said hardware setting information is inputted from said specific interface as a select signal for controlling said second multiplexer circuit to select said clock signal, based on a setting request signal supplied from said setting means, when said enable signal is received from said specific

testing module.

7. A testing apparatus as claimed in claim 2, further comprising:

a first site controlling apparatus for controlling a first testing module among said testing modules; and

a second site controlling apparatus for controlling a second testing module among said testing modules,

wherein said enable signal controlling means instructs said first testing module to generate and supply said enable signal to a first controlling module among said controlling modules, said first controlling module supplying said control signal to said first testing module, and said second testing module to generate and supply said enable signal to a second controlling module among said controlling modules, said second controlling module supplying said control signal to said second testing module,

said setting information supplying means supplies said hardware setting information via a first interface among said interfaces, said first interface inputting said control signal generated under the control of said first site controlling apparatus to said first controlling module, and via a second interface among said interfaces, said second interface inputting said control signal generated under the control of said second site controlling apparatus to said second controlling module, and

said setting means sets said first controlling module to supply said control signal to said first testing module, said control signal being inputted from said first interface to said first controlling module, and said second controlling module to supply said control signal to said second testing module,

said control signal being inputted from said second interface to said second controlling module.

8. A testing apparatus as claimed in claim 2, wherein said testing apparatus tests a plurality of said devices under test at the same time,

said enable signal controlling means instructs a first testing module among said testing modules to generate and supply said enable signal to a first controlling module among said controlling modules, said first testing module supplying said test signal to a first device under test among said devices under test, said first controlling module supplying said control signal to said first testing module, and a second testing module among said testing modules to generate and supply said enable signal to a second controlling module among said controlling modules, said second testing module supplying said test signal to a second device under test among said devices under test, said second controlling module supplying said control signal to said second testing module,

said setting information supplying means supplies said hardware setting information via a first interface among said interfaces, said first interface inputting said control signal for controlling the test of said first device under test to said first controlling module, and via a second interface among said interfaces, said second interface inputting said control signal for controlling the test of said second device under test to said second controlling module, and

said setting means sets said first controlling module to supply said control signal to said first testing module, said control signal being inputted from said first interface to said first controlling module, and said second controlling module

to supply said control signal to said second testing module, said control signal being inputted from said second interface to said second controlling module.

9. A testing apparatus as claimed in claim 1, wherein said testing modules are analog measuring modules for performing an analog test of said device under test, and

said controlling modules supply a control signal to each of said analog measuring modules, said control signal being used for controlling said analog measuring modules.